

Anton Paar announces new software product **Tosca™ Analysis** for industrial AFM users

Powered by Digital Surf's Mountains® technology platform

Graz, Austria & Besançon, France: Following the recent launch of the Tosca™ 400 atomic force microscope, the leading scientific equipment manufacturing company Anton Paar is today announcing the launch of **Tosca™ analysis software**, based on Digital Surf's Mountains® surface analysis technology.

Specially designed for industrial users, the Tosca™ 400 comes with Tosca™ Control software for operating the AFM. Add to that new **Tosca™ analysis software** and users now have a complete solution for complex nano-surface analysis in a wide variety of application areas including characterization of semiconductor properties and investigation of polymer chains.



Tosca™ analysis software for Tosca™ 400 AFM

Main features include:

- **Real-time 3D multi-channel imaging with overlays**
- **Characterization of surface texture** using the latest 3D parameters defined in the ISO 25178 standard
- **State-of-the-art geometry & morphology analysis at the nanoscale** including height of grains and motifs, volume of surface structures (bumps, holes), step heights etc.
- **Powerful automation features for demanding applications** including critical dimensioning & statistics
- **Co-localization of surface data from other analyses for correlative analysis** e.g. Raman chemical maps

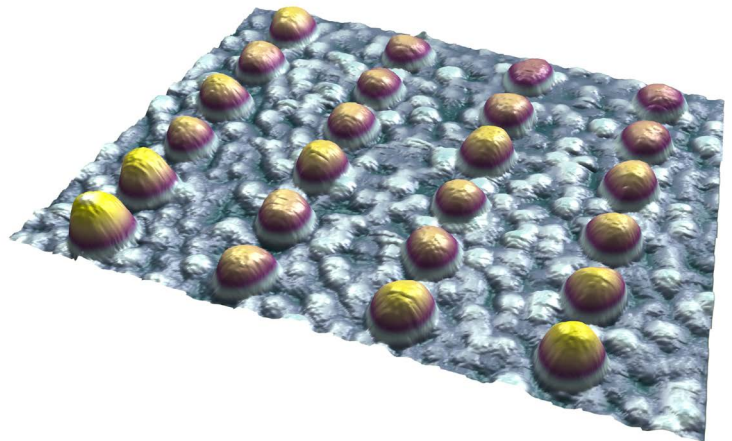
Available in 11 different languages, Tosca™ analysis software comes with a user-friendly ribbon interface and contextual tabs with intuitive icon-based tools.

The interactive workflow allows full metrological traceability and easy fine-tuning at any time.

Generating surface analysis reports in Excel, PDF and Word-compatible RTF formats has never been easier.

Additionally, automation tools help speed up production (for example analysis routines can be saved as templates and re-applied to batches.)

Read more: www.anton-paar.com/corp-en/products/details/afm-software-toscatm-control-and-toscatm-analysis/



Lithographic patterns of aluminum nanoparticles on ITO coated glass
(3D view of sample generated using Tosca™ analysis software)



Anton Paar develops, produces and distributes highly accurate laboratory instruments and process measuring systems, and provides custom-tailored automation and robotic solutions.

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Digital Surf is the editor of Mountains® surface metrology and analysis software solutions for profilers and microscopes, integrated by leading instrument manufacturers worldwide.

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